



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No. : 10/689,314

Applicant : David Berman et al.

Filed : October 20, 2003

Title : X-RAY REFLECTOMETRY OF THIN FILM LAYERS
WITH ENHANCED ACCURACY

Art Unit : 2882

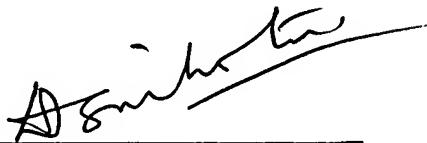
Docket No. : 22350/21

Customer No. : 1912

STATEMENT OF LACK OF DECEPTIVE INTENTION

I was mistakenly omitted as a co-inventor with David Berman and Alex Dikopoltsev on the above-identified patent application, and the error in inventorship occurred without deceptive intention on my part.

Dated: 20th Oct, 2005


Dileep Agnihotri